



WEBINARS

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High-Resolution Measurement of Film Thickness and Refractive Index for Silicon Photonics and Planar Waveguide Applications

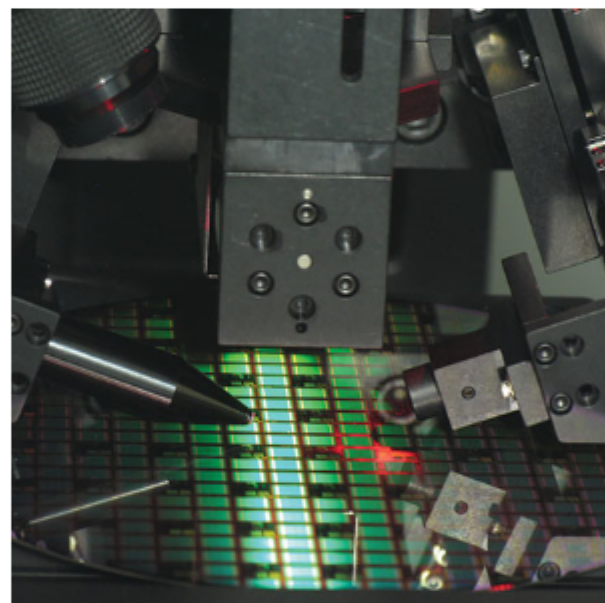
Wednesday, December 6, 2023 1:00 PM - 2:00 PM EST

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Presented by



This webinar provides an overview of advanced measurement technologies tailored to meet the high-resolution demands of silicon photonics and planar waveguide applications. Lawrence Rooney of Bruker shares about state-of-the-art film thickness and refractive index measurement techniques, including multi-angle spectroscopic reflectometry and ellipsometry, and discusses their respective advantages, limitations, and suitability for different types of multi-layer photonic structures. He also highlights the critical importance of high-resolution film thickness and refractive index measurement techniques in the advancement of silicon photonics and planar waveguide applications. Presented by [Bruker](#).



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